L Number	Hits	Search Text	DB	Time stamp
1	219	SEM and objective adj lens and beam and secondary adj electron and	USPAT;	2004/03/11 08:59
		deflect\$5 and (detect\$5 analyz\$5)	ЕРО; ЛРО;	
.	_		DERWENT	
5	0	(((SEM and objective adj lens and beam and secondary adj electron and	USPAT;	2004/03/11 08:51
		deflect\$5 and (detect\$5 analyz\$5)) and 250/\$.ccls.) and auger) and	ЕРО; ЛРО;	
	10	sheild	DERWENT	2004/02/11 00:51
2	10	(((SEM and objective adj lens and beam and secondary adj electron and deflect\$5 and (detect\$5 analyz\$5)) and 250/\$.ccls.) and auger) and	USPAT; EPO; JPO;	2004/03/11 08:51
		shield	DERWENT	
	190	(SEM and objective adj lens and beam and secondary adj electron and	USPAT;	2004/03/11 09:03
	170	deflect\$5 and (detect\$5 analyz\$5)) and 250/\$.ccls.	ЕРО; ЛРО;	200 1/03/11 07:03
		and (accords analyzes)) and 25 or 6.0015.	DERWENT	
6	6	SEM and lens and beam and secondary adj electron and deflect\$5 and	USPAT;	2004/03/11 09:26
		(detect\$5 analyz\$5) and secondary adj optical	ЕРО; ЛРО;	
			DERWENT	
7	0	(SEM and lens and beam and secondary adj electron and deflect\$5 and	USPAT;	2004/03/11 08:59
		(detect\$5 analyz\$5) and secondary adj optical) and auger	ЕРО; ЈРО;	
			DERWENT	
3	27	((SEM and objective adj lens and beam and secondary adj electron and	USPAT;	2004/03/11 08:59
		deflect\$5 and (detect\$5 analyz\$5)) and 250/\$.ccls.) and auger	ЕРО; ЛРО;	
	40	((OT) (- 1 1	DERWENT	2004/02/11 05 6
9	48	((SEM and objective adj lens and beam and secondary adj electron and	USPAT;	2004/03/11 09:04
		deflect\$5 and (detect\$5 analyz\$5)) and 250/\$.ccls.) and shield\$5	EPO; JPO;	
	52	SEM and lens and beam and secondary adj electron and deflect\$5 and	DERWENT USPAT;	2004/03/11 09:26
9	32	(detect\$5 analyz\$5) and auger	EPO; JPO;	2004/03/11 09.20
		(detects analyzes) and auger	DERWENT	
10	0	(SEM and lens and beam and secondary adj electron and deflect\$5 and	USPAT;	2004/03/11 09:26
	Ů	(detect\$5 analyz\$5) and auger) and virtual same auger	EPO; JPO;	200 1103/11 07:20
		(DERWENT	
-	33	SEM and objective adj lens and beam and secondary adj electron and	USPAT;	2004/03/11 08:50
		auger	ЕРО; ЛРО;	
			DERWENT	
-	26	(SEM and objective adj lens and beam and secondary adj electron and	USPAT;	2003/10/17 13:55
		auger) and analy\$6	ЕРО; ЛРО;	
	10	(orac all all all all all all all all all a	DERWENT	2002/10/17 11 24
-	10	((SEM and objective adj lens and beam and secondary adj electron and	USPAT;	2003/10/17 11:34
		auger) and analy\$6) and shield	EPO; JPO; DERWENT	
_	20	((SEM and objective adj lens and beam and secondary adj electron and	USPAT;	2003/10/17 14:00
	20	auger) and analy\$6) and resolution	EPO; JPO;	2003/10/17 14:00
			DERWENT	
-	9	((SEM and objective adj lens and beam and secondary adj electron and	USPAT;	2003/10/17 14:00
		auger) and analy\$6) and magnetic adj field	ЕРО; ЛРО;	
			DERWENT	
-	1	(SEM and objective adj lens and beam and secondary adj electron and	USPAT;	2003/10/17 14:36
		auger) and capacitor same image	ЕРО; ЈРО;	
			DERWENT	
-	38	SEM and objective adj lens and beam and auger	USPAT;	2003/10/17 14:36
			EPO; JPO;	
	1	(SEM and abjective editions and beam and average and accessive	DERWENT	2002/10/17 14:59
-	ı	(SEM and objective adj lens and beam and auger) and capacitor same image	USPAT; EPO; JPO;	2003/10/17 14:58
		I mage	DERWENT	
-	1	(SEM and objective adj lens and beam and auger) and electrostatic adj	USPAT;	2003/10/17 14:59
	•	capacitor	EPO; JPO;	
			DERWENT	
-	18	(SEM and objective adj lens and beam and auger) and electrostatic	USPAT;	2003/10/17 14:59
			ЕРО; ЛРО;	
			DERWENT	
-	123	((scanning adj electron adj microscope) SEM) and Auger and optic\$5	USPAT;	2004/03/10 15:25
		and lens and (detect\$5 analyz\$5)	EPO; JPO;	
		<u> </u>	DERWENT	1